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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2812
Examiner: Unassigned

In re PATENT APPLICATION of

Applicant : Masakatsu SAIJYO et al.

Appl. No. : 10/648,343

Filed : August 27, 2003

For : METHOD OF MEASURING CONTACT
RESISTANCE OF PROBE AND METHOD OF
TESTING SEMICONDUCTOR DEVICE

Atty. Dkt. : OKI 373

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)
) **INFORMATION**
) **DISCLOSURE**
) **STATEMENT**
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)
)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This is an information disclosure statement submitted in compliance with the timing requirements of 37 C.F.R. §1.97(b)(3), i.e., prior to a first Office Action on the merits.

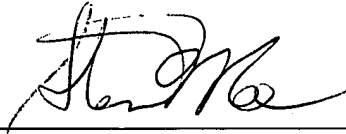
Attached are copies of three Japanese patent publications, and a Japanese Office Action dated April 6, 2004. Also attached are English-language abstracts of the Japanese patent publications and English-language translation of the Japanese Office Action, from which any relevance of the documents may be gleaned. Listed for consideration is one U.S. patent, any relevance of which is self-evident. The U.S. patent and the Japanese patent publications are listed on the attached Form PTO-1449.

Since this Information Disclosure Statement is being filed before a first Office Action, no certification or fee is required, and the requirements of 37 C.F.R. §§1.97 and 1.98 are deemed to be fully met as to all documents listed. Consideration of the listed documents respectfully is requested.

FEE ENCLOSED: \$0
Please charge any further
fee to our Deposit Account
No. 18-0002

Should any fee be required, please charge the same to our Deposit Account No. 18-0002 and advise us accordingly.

Respectfully submitted,



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CUSTOMER NO. 23995

June 4, 2004

Date

SMR:vm



FORM PTO-1449 INFORMATION DISCLOSURE STATEMENT				Atty. Docket OKI 373		Application No. 10/648,343	
				Applicant Masakatsu SAIJYO et al.			
				Filing Date August 27, 2003		Group 2812	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
	AA	6,087,895	07/11/00	ONO			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Sub-Class	Translation
	AI	10-107104	04/24/98	JAPAN			Abstract
	AJ	09-275191	10/21/97	JAPAN			Abstract
	AK	10-209231	08/07/98	JAPAN			Abstract
	AL						
	AM						
	AN						
OTHER (Including Author, Title, Date, Pertinent Pages, etc.)							
	AO						
Examiner					Date Considered		
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							